

Gd₂OSe₂

Olivier Tougait and James A. Ibers*

Department of Chemistry, Northwestern University, 2145 Sheridan Rd, Evanston, IL 60208-3113, USA

Correspondence e-mail: iberns@chem.nwu.edu

Received 22 December 1999

Accepted 24 February 2000

Single crystals of digadolinium monooxygen diselenide, Gd₂OSe₂, have been obtained from a KBr flux. The compound is isostructural with the low-pressure form of Dy₂OSe₂. All atoms lie on the mirror plane of *Pnma*. The Gd environments are a GdO₃Se₅ bicapped trigonal prism and a GdOSe₅ distorted octahedron. The two coordination polyhedra pack by face-sharing and edge-sharing to form a [Gd_{8/4}O_{4/4}Se_{8/8}^a-Se_{8/8}ⁱ] fragment, which is the main motif of the structure. These fragments lie in the *ac* plane and form infinite chains parallel to *c* through the sharing of Se atoms around atom Gd1. In the *a* direction, these chains stack through the sharing of an Se atom around atom Gd2, thereby delimiting large pentagonal cavities.

Comment

Rare-earth oxychalcogenides are of particular interest for their use as phosphors. Suitable material for efficient conversion of X-rays to light are Gd₂O₂S doped with Tb and Y₂O₂S doped with Eu.

Rare-earth monooxygen disulfides, Ln₂OSe₂ (Ln = rare earth), exhibit two different structure types. The first is the Tm₂OSe₂ structure type (monoclinic, *P2₁/c*) adopted by Er, Tm, Yb (Range *et al.*, 1990), Dy (Schleid, 1991), Y (Schleid, 1992) and Sm (Lissner & Schleid, 1992). The crystal structure is built from the close packing of two mixed LnQ₇ (Q = O, S) polyhedra and shows some similarities to the structures of rare-earth sesquichalcogenides. The second is the low-temperature Dy₂OSe₂ structure type (orthorhombic, *Pnma*) (Schleid, 1991). The title compound, Gd₂OSe₂, is isotypic to this second structure type and represents the first rare-earth monooxygen diselenide to be characterized by single-crystal X-ray crystallography.

A displacement ellipsoid diagram of Gd₂OSe₂ is shown in Fig. 1. GdO₃Se₅ bicapped trigonal prisms and GdOSe₅ distorted octahedra pack by face-sharing and edge-sharing to form a [Gd_{8/4}O_{4/4}Se_{8/8}^aSe_{8/8}ⁱ] (*i* = inner and *a* = apical) fragment that constitutes the main building motif of the structure. These fragments, which lie in the *ac* plane, form infinite chains parallel to the *c* axis by sharing Se atoms around atom Gd1. In the *a* direction, these chains stack by sharing Se atoms around

atom Gd2, delimiting pentagonal cavities. In the *b* direction, the three-dimensional interconnection occurs *via* face-sharing of trigonal prisms and edge-sharing of octahedra.

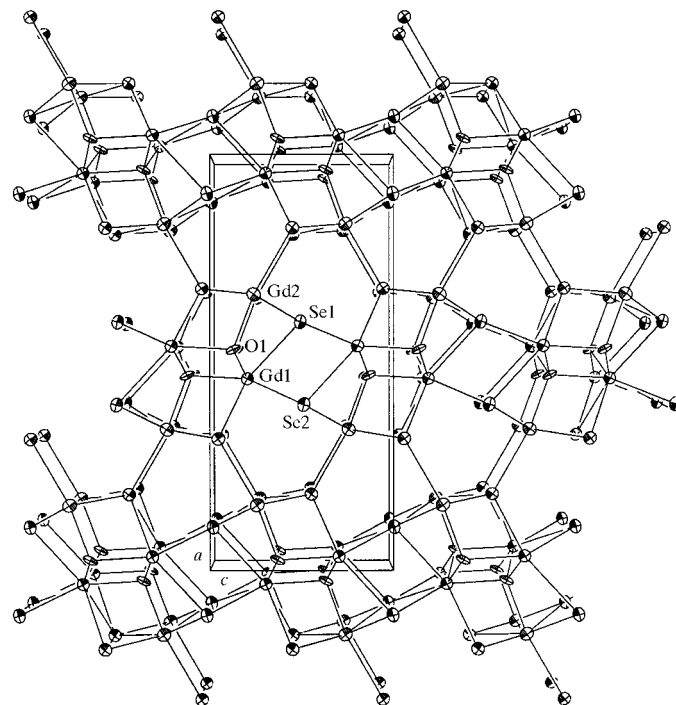


Figure 1

View of the structure of Gd₂OSe₂ down *b*. Displacement ellipsoids are drawn at the 90% probability level.

Experimental

Single crystals of Gd₂OSe₂ were obtained as a side product of the reaction of Gd (0.290 g, Alfa, 99.9%), TiO₂ (0.029 g, Alfa, 99.9%), Ti (0.017 g, Alfa, 99.9%) and Se (0.228 g, Alfa, 99.5%), with KBr (200 mg, Alfa, 99%) added to promote crystal growth. The materials were mixed and sealed in a fused-silica tube that was then evacuated to 10⁻⁴ Torr (1 Torr = 133.322 Pa). The tube was heated to 1223 K for 4 d before being cooled to 973 K at the rate of 3 K h⁻¹ when the furnace was turned off. The final product was washed with methanol and water, and dried with acetone. Yellow single crystals of Gd₂OSe₂ of rod-like habit were found. Qualitative energy dispersive spectroscopy (EDS) analysis verified the presence of Gd, Se, and O.

Crystal data

Gd₂OSe₂
M_r = 488.42
 Orthorhombic, *Pnma*
a = 16.050 (3) Å
b = 3.9375 (8) Å
c = 7.0309 (14) Å
V = 444.32 (15) Å³
Z = 4
D_x = 7.301 Mg m⁻³

Mo *K*α radiation
 Cell parameters from 2878 reflections
 θ = 2.54–28.29°
 μ = 45.78 mm⁻¹
T = 153 (2) K
 Rod, pale yellow
 0.240 × 0.024 × 0.022 mm

Data collection

Bruker Smart 1000 CCD diffractometer	623 independent reflections
ω scans	$R_{\text{int}} = 0.034$
Absorption correction: numerical (face indexed; <i>SHELXTL/PC</i> ; Sheldrick, 1997)	$\theta_{\text{max}} = 28.29^\circ$
$T_{\text{min}} = 0.065$, $T_{\text{max}} = 0.400$	$h = -20 \rightarrow 20$
3870 measured reflections	$k = -5 \rightarrow 5$
	$l = -9 \rightarrow 9$
	Intensity decay: <2%

Refinement

Refinement on F^2	$(\Delta/\sigma)_{\text{max}} < 0.001$
$R[F^2 > 2\sigma(F^2)] = 0.024$	$\Delta\rho_{\text{max}} = 2.96 \text{ e } \text{\AA}^{-3}$
$wR(F^2) = 0.059$	$\Delta\rho_{\text{min}} = -2.30 \text{ e } \text{\AA}^{-3}$
$S = 1.101$	Extinction correction:
623 reflections	<i>SHELXTL/PC</i> (Sheldrick, 1997)
32 parameters	Extinction coefficient: 0.0017 (2)
$w = 1/[\sigma^2(F_o^2) + (0.04F_o^2)^2]$	

Data collection: *SMART* (Bruker, 1999); cell refinement: *SMART*; data reduction: *SAINT-Plus* (Bruker, 1999); program(s) used to solve structure: *SHELXS97* (Sheldrick, 1990); program(s) used to refine structure: *SHELXTL/PC* (Sheldrick, 1997); molecular graphics: *SHELXTL/PC*; software used to prepare material for publication: *SHELXTL/PC*.

Use was made of the scanning electron microscope facility supported by the US National Science Foundation through the Northwestern University Materials Research Center (grant DMR96-32472). This research was supported by the US

Table 1

Selected geometric parameters (\AA).

Gd1—O1	2.317 (6)	Gd2—O1	2.240 (5)
Gd1—O1 ⁱ	2.326 (3)	Gd2—Se2 ^{vi}	2.8183 (7)
Gd1—O1 ⁱⁱ	2.326 (3)	Gd2—Se2 ^{vii}	2.8183 (7)
Gd1—Se2 ⁱⁱⁱ	3.0228 (10)	Gd2—Se1 ^{iv}	2.8642 (8)
Gd1—Se2 ^{iv}	3.0932 (8)	Gd2—Se1 ^v	2.8642 (8)
Gd1—Se2 ^v	3.0932 (8)	Gd2—Se1	2.9203 (10)
Gd1—Se1 ^{iv}	3.1726 (8)	Gd2—Gd1 ⁱ	3.7968 (7)
Gd1—Se1 ^v	3.1726 (8)		

Symmetry codes: (i) $-x, -y, 1 - z$; (ii) $-x, 1 - y, 1 - z$; (iii) $x - \frac{1}{2}, y, \frac{3}{2} - z$; (iv) $\frac{1}{2} - x, 1 - y, \frac{1}{2} + z$; (v) $\frac{1}{2} - x, -y, \frac{1}{2} + z$; (vi) $\frac{1}{2} - x, -y, z - \frac{1}{2}$; (vii) $\frac{1}{2} - x, 1 - y, z - \frac{1}{2}$.

National Science Foundation under grant DMR97-09351. We acknowledge the assistance of Dr P. G. Jene.

Supplementary data for this paper are available from the IUCr electronic archives (Reference: BR1282). Services for accessing these data are described at the back of the journal.

References

- Bruker (1999). *SMART* (Version 5.054) and *SAINT-Plus* (Version 6.01). Bruker AXS Inc., Madison, Wisconsin, USA.
- Lissner, F. & Schleid, T. (1992). *Z. Naturforsch. Teil B*, **47**, 1614–1620.
- Range, K.-J., Lange, K. G. & Gietl, A. (1990). *J. Less Common Met.* **158**, 137–145.
- Schleid, T. (1991). *Z. Anorg. Allg. Chem.* **602**, 39–47.
- Schleid, T. (1992). *Eur. J. Solid State Inorg. Chem.* **29**, 1015–1028.
- Sheldrick, G. M. (1990). *Acta Cryst.* **A46**, 467–473.
- Sheldrick, G. M. (1997). *SHELXTL/PC*. Version 5.101. Siemens Analytical X-ray Instruments Inc., Madison, Wisconsin, USA.